

Abstract Submitted
for the NEF07 Meeting of
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Nanocharacterization: Atomic Scale Visualization with Microscopy CHRISTINE BROADBRIDGE — This workshop will include an overview presentation of nanotechnology and nanocharacterization tools (electron microscopy and atomic force microscopy) as well as examples of curricular components for middle and high school teachers. Tours/demonstrations of microscopy facilities in the IMS facility at UConn will be provided.

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